

Resource Summary Report

Generated by [RRID](#) on Aug 6, 2026

FEI: Themis Z for Materials Science

RRID:SCR_019910

Type: Tool

Proper Citation

FEI: Themis Z for Materials Science (RRID:SCR_019910)

Resource Information

URL: <https://www.fei.com/products/tem/themis-z-for-materials-science/>

Proper Citation: FEI: Themis Z for Materials Science (RRID:SCR_019910)

Description: Next generation, ultra-high resolution, aberration corrected, scanning transmission electron microscope delivering the ultimate optical performance and flexibility with unprecedented reproducibility.

Resource Type: instrument resource

Keywords: FEI, TEM, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Themis Z for Materials Science

Resource ID: SCR_019910

Alternate IDs: Model_Number_Themis Z

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190639+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Themis Z for Materials Science.

No alerts have been found for FEI: Themis Z for Materials Science.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.